

°C/W

80

650V Super-Junction Power MOSFET

FEATURES

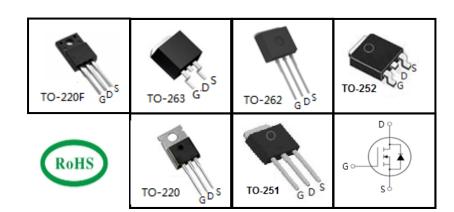
- Very low FOM $R_{DS(on)} \times Q_g$
- 100% avalanche tested
- RoHS compliant

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)

Thermal Resistance, Junction-to-Ambient

Power Factor Correction (PFC)



Device Marking and Package Information						
Device	TPA65R940C	TPB65R940C	TPC65R940C	TPD65R940C	TPP65R940C	TPU65R940C
Package	TO-220F	TO-263	TO-262	TO-252	TO-220	TO-251
Marking	65R940C	65R940C	65R940C	65R940C	65R940C	65R940C

Absolute Maximum Ratings $T_C = 25^{\circ}$	C, un	less other\	vise noted		
Parameter		Symbol	Value		
			TO-220, TO-251, TO-252 TO-262, TO-263	TO-220F	Unit
Drain-Source Voltage (V _{GS} = 0V)		$V_{\rm DSS}$	650		V
Continuous Drain Current $T_C = 25^{\circ}C$		ı	4		۸
$T_C = 100^{\circ}C$		I _D	2.4		A
Pulsed Drain Current (note1)	I _{DM}	12		Α
Gate-Source Voltage		V_{GSS}	±30		V
Single Pulse Avalanche Energy (note2)		E _{AS}	52.8		mJ
Avalanche Current (note1)	I _{AS}	0.8		Α
MOSFET dv/dt ruggedness, $V_{DS} = 0480V$		dv/dt	50		V/ns
Reverse diode dv/dt, $V_{DS} = 0480V$, $I_{SD} \le I_{D}$		dv/dt	15		V/ns
Power Dissipation ($T_C = 25^{\circ}C$)		P_{D}	28	23	W
Operating Junction and Storage Temperature Range		T_J,T_stg	-55~+150		°C
Thermal Resistance					
Parameter			Value		
		Symbol	TO-220, TO-251, TO-252 TO-262, TO-263	TO-220F	Unit
Thermal Resistance, Junction-to-Case		R_{thJC}	4.4	5.5	00/1/

 R_{thJA}

62



TPA65R940C, TPB65R940C, TPC65R940C, TPD65R940C, TPP65R940C, TPU65R940C

Wuxi Unigroup Microelectronics Company

Specifications $T_J = 25^{\circ}C$, ur	ness otne	rwise noted I I				
Parameter	Symbol	Test Conditions	Value			Unit
			Min.	Тур.	Max.	
Static						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	650			V
Zero Gate Voltage Drain Current		$V_{DS} = 650V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1	
Zero Gate Voltage Drain Guirent	I _{DSS}	$V_{DS} = 650V, V_{GS} = 0V, T_{J} = 150^{\circ}C$			100	μΑ
Gate-Source Leakage	I _{GSS}	$V_{GS} = \pm 30V$			±100	nA
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.5		4.0	V
Drain-Source On-Resistance (Note3)	R _{DS(on)}	V _{GS} = 10V, I _D = 1A		0.88	1.0	Ω
Forward Transconductance (Note3)	g _{fs}	$V_{DS} = 10V, I_{D} = 1A$		3		S
Dynamic		•				
Input Capacitance	C _{iss}	$V_{GS} = 0V$, $V_{DS} = 50V$,		360		pF
Output Capacitance	C _{oss}			23		
Reverse Transfer Capacitance	C _{rss}	f = 1.0MHz		2.8		
Total Gate Charge	Q_g			7		nC
Gate-Source Charge	Q_{gs}	$V_{DD} = 520V, I_{D} = 4A,$ $V_{GS} = 10V$		1.5		
Gate-Drain Charge	Q_{gd}	GS . G		2.5		
Turn-on Delay Time	t _{d(on)}			36		
Turn-on Rise Time	t _r	$V_{DD} = 400V, I_{D} = 4A,$		27		
Turn-off Delay Time	t _{d(off)}	$R_G = 25\Omega$		79		ns
Turn-off Fall Time	t _f			29		
Drain-Source Body Diode Characteris	stics			•		
Continuous Body Diode Current	Is	T 0500			4	
Pulsed Diode Forward Current	I _{SM}	$T_C = 25^{\circ}C$			12	Α
Body Diode Voltage	V _{SD}	$T_J = 25^{\circ}C$, $I_{SD} = 4A$, $V_{GS} = 0V$		0.9	1.2	V
Reverse Recovery Time	t _{rr}			220		ns
Reverse Recovery Charge	Q _{rr}	$V_R = 480V, I_F = I_S,$ $di_F/dt = 100A/\mu s$		0.9		μC
Peak Reverse Recovery Current	I _{rrm}			8		Α

Notes

- 1. Repetitive Rating: Pulse Width limited by maximum junction temperature
- 2. I_{AS} = 0.8A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25 $^{\circ}$ C
- 3. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 1%

Typical Characteristics $T_J = 25^{\circ}C$, unless otherwise noted

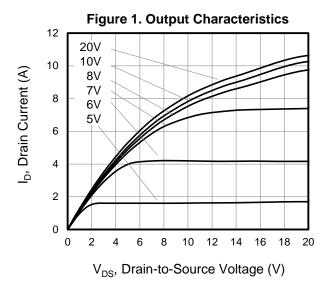


Figure 3. On-Resistance vs. Drain Current

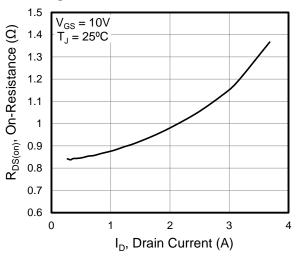


Figure 5. Gate Charge

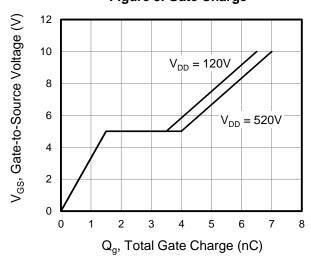


Figure 2. Transfer Characteristics

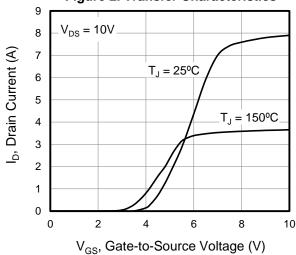


Figure 4. Capacitance

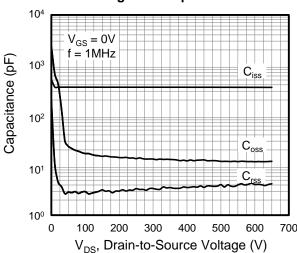
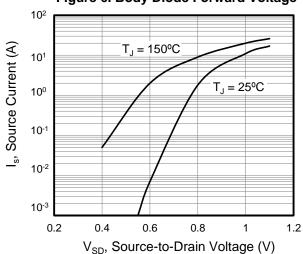
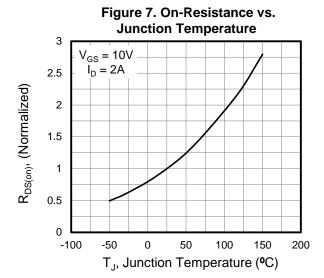


Figure 6. Body Diode Forward Voltage





Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted



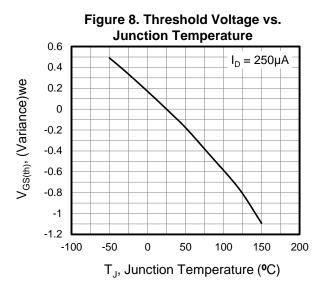
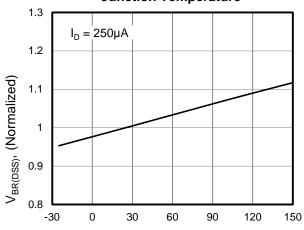


Figure 9. Breakdown voltage vs. Junction Temperature



T_J, Junction Temperature (°C)



Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted

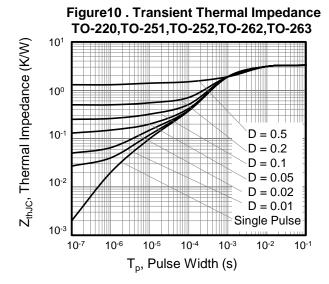


Figure 12. Safe operation area for

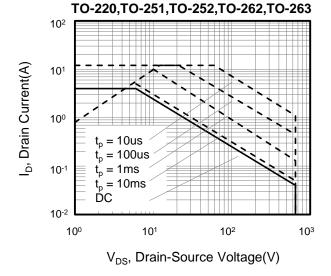


Figure 11. Transient Thermal Impedance

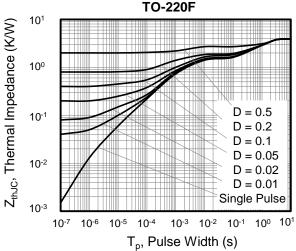
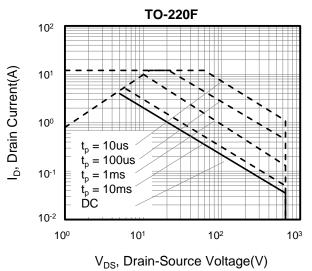


Figure 13. Safe operation area for



V3.2 5 www.tsinghuaicwx.com



Figure A: Gate Charge Test Circuit and Waveform

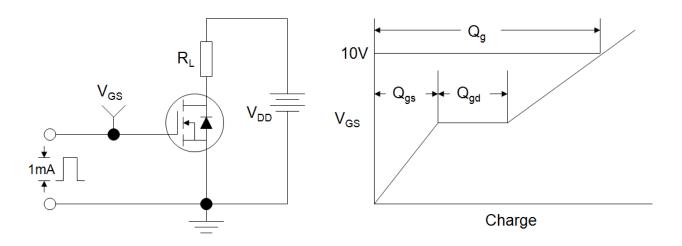


Figure B: Resistive Switching Test Circuit and Waveform

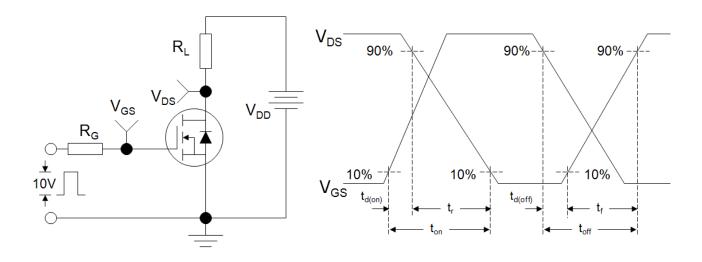
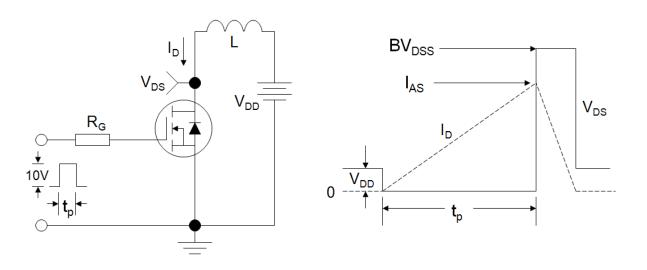
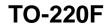


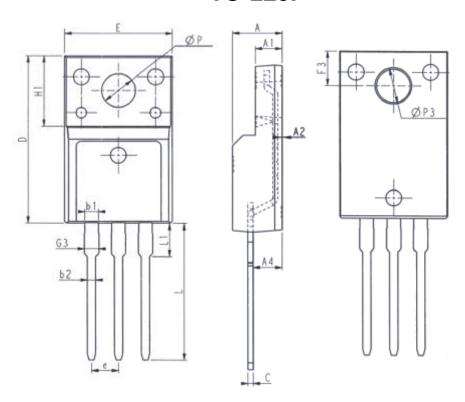
Figure C: Unclamped Inductive Switching Test Circuit and Waveform



V3.2 6 www.tsinghuaicwx.com



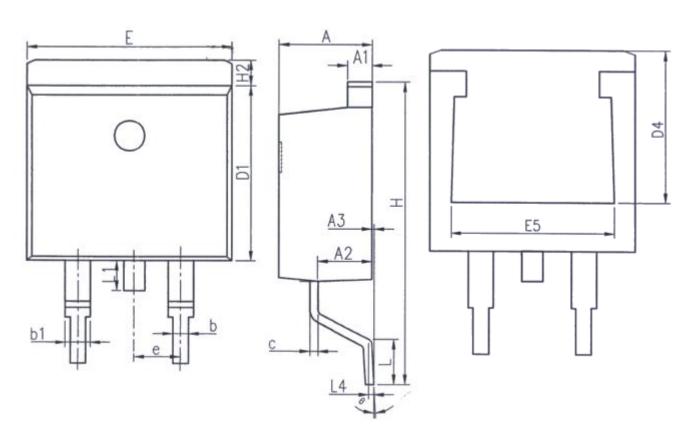




Unit: mm			l	Jnit: mn	n
Symbol	Min.	Max.	Symbol	Min.	Max.
E	9. 96	10.36	L	12. 68	13. 28
Α	4. 50	4. 90	L1	2. 93	3. 13
A 1	2. 34	2. 74	Р	3. 03	3. 38
A2	0.30	0. 60	Р3	3. 15	3. 65
A4	2. 56	2. 96	F3	3. 15	3. 45
С	0.40	0. 65	G3	1. 25	1. 55
D	15. 57	16. 17	b1	1. 18	1. 43
H1	6. 70REF		b2	0. 70	0. 95
е	2. 54BSC				



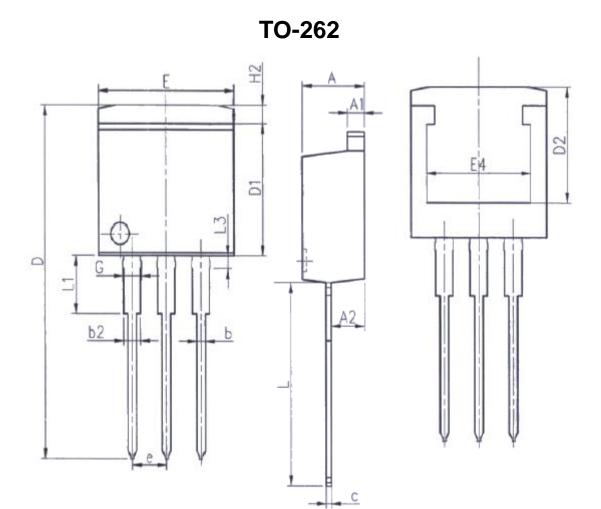




Unit: mm					
Symbol	Min.	Max.			
Α	4. 37	4. 77			
A 1	1. 22	1. 42			
A2	2. 49	2. 89			
A3	0. 00	0. 25			
b	0. 70	0. 96			
b1	1. 17	1. 47			
С	0. 30	0. 53			
D1	8. 50	8. 90			
D4	6. 60	_			

Unit: mm					
Symbol	Min.	Max.			
E	9.86	10.36			
E 5	7. 06	-			
е	2. 54BSC				
Н	14. 70	15. 50			
H2	1. 07	1. 47			
L	2.00	2. 60			
L1	1. 40	1. 70			
L4	0. 25BSC				
θ	0°	9°			

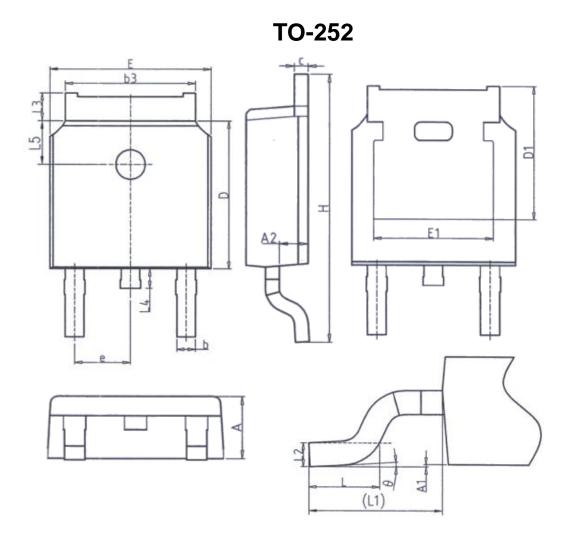




Unit: mm					
Symbol	Min.	Max.			
Α	4. 37	4. 77			
A1	1. 22	1. 42			
A2	2. 47	2. 87			
b	0. 70	0. 97			
b2	1. 17	1. 42			
С	0. 28	0.53			
D	23. 20	24. 02			
D1	8. 38	8. 90			
D2	6. 00	-			

Unit: mm					
Symbol	Min.	Max.			
E	9. 90	10.39			
E4	7. 30	_			
е	2. 54BSC				
G	1. 25	1.50			
H2	-	1. 31			
L	13. 34	14. 10			
L1	3. 30	4. 06			
L3	0. 95	1. 15			



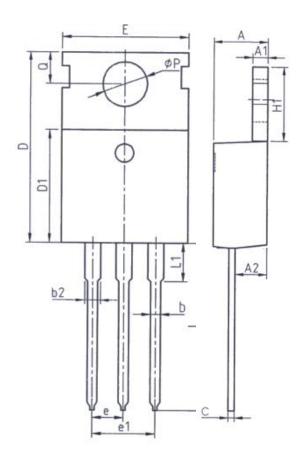


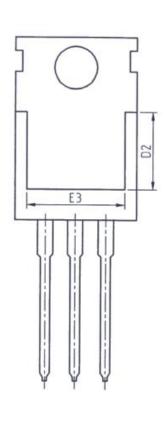
Unit: mm					
Symbol	Min.	Max.			
Α	2. 20	2. 40			
A1	0.00	0. 20			
A2	0. 97	1. 17			
b	0. 68	0.90			
b3	5. 20	5. 50			
С	0. 43	0. 63			
D	5. 98	6. 22			
D1	REF				
E	6. 40	6. 80			
E1	4. 63	_			

Unit: mm					
Symbol	Min.	Max.			
е	2. 286BSC				
Н	9. 40	10.50			
L	1. 38	1. 75			
L1	2. 90REF				
L2	0. 51	IBSC			
L3	0.88	1. 28			
L4	- 1.00				
L5	1. 65 1. 95				
θ	θ 0°				



TO-220



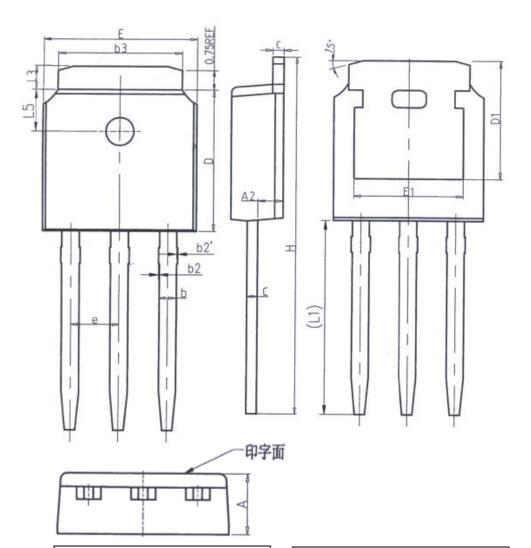


Unit: mm					
Symbol	Min.	Max.			
Α	4. 37	4. 77			
A1	1. 25	1. 45			
A2	2. 20	2. 60			
b	0. 70	0. 95			
b2	1. 17	1. 47			
С	0. 40	0. 65			
D	15. 10	16. 10			
D1	8. 80	9. 40			
D2	5. 50	_			

Unit: mm					
Symbol	Min.	Max.			
E	9. 70	10. 30			
E3	7. 00	ı			
е	2. 54BSC				
e1	5. 08BSC				
H1	6. 25 6. 8				
L	12. 75	13.80			
L1	-	3. 40			
P	3. 40	3. 80			
Q	2. 60	3. 00			



TO-251



Unit: mm		
Symbol	Min.	Max.
Α	2. 20	2. 40
A2	0. 97	1. 17
b	0. 68	0.90
b2	0.00	0.10
b2′	0.00	0.10
b3	5. 20	5. 50
С	0. 43	0. 63
D	5. 98	6. 22

Unit: mm		
Symbol	Min.	Max.
D1	5. 30REF	
E	6. 40	6. 80
E1	4. 63	-
е	2. 286BSC	
Н	16. 22	16. 82
L1	9. 15	9. 65
L3	0.88	1. 28
L5	1. 65	1. 95





Disclaimer

All product specifications and data are subject to change without notice.

For documents and material available from this datasheet, Wuxi Unigroup does not warrant or assume any legal liability or responsibility for the accuracy, completeness of any product or technology disclosed hereunder.

No license, express or implied, by estoppels or otherwise, to any intellectual property rights is granted by this document or by any conduct of Wuxi Unigroup.

The products shown herein are not designed for use in medical, life-saving, or life-sustaining applications. Customers using or selling Wuxi Unigroup products not expressly indicated for use in such applications do so entirely at their own risk and agree to fully indemnify Wuxi Unigroup for any damages arising or resulting from such use or sale.

Wuxi Unigroup disclaims any and all liability arising out of the use or application of any product described herein or of any information provided herein to the maximum extent permitted by law. The product specifications do not expand or otherwise modify Wuxi Unigroup's terms and conditions of purchase, including but not limited to the warranty expressed therein, which apply to these products.

Wuxi Unigroup Microelectronics CO., LTD. strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.

In the event that any or all Wuxi Unigroup products (including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.

Information (including circuit diagrams and circuit parameters) herein is for example only. It is not guaranteed for volume production. Wuxi Unigroup believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.